

Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 12732-207001	Application No. 10/756,756 New Application
<b>Information Disclosure Statement by Applicant</b> (Use several sheets if necessary)  (37 CFR §1.98(b))		Applicant Hajime Kimura et al.	
		Filing Date January 14, 2004	Group Art Unit 2673

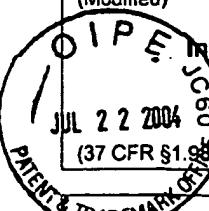
U.S. Patent Documents							
Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

Foreign Patent Documents or Published Foreign Patent Applications							
Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation
							Yes No
DD	AL	2003-066909	03/05/2003	JAPAN	—	—	ABS
DD	AM	2003-150112	05/23/2003	JAPAN	—	—	ABS
DD	AN	2003-195812	07/09/2003	JAPAN	—	—	ABS
	AO						
	AP						

Other Documents (include Author, Title, Date, and Place of Publication)		
Examiner Initial	Desig. ID	Document
DD	AQ	Reiji Hattori et al.; "Circuit Simulation of Poly-Si TFT Based Current-writing Active-Matrix Organic LED Display"; <i>Technical Report of IEICE, ED2001-8, SDM2001-8</i> ; The Institute of Electronics, Information and Communication Engineers, pp. 7-14; 2001
	AR	
	AS	
	AT	

Examiner Signature	Jeff Piziali	Date Considered	6-20-2005
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.			

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		Filing Date January 14, 2004	Group Art Unit <i>2673</i>	

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**Other Documents (include Author, Title, Date, and Place of Publication)**

Examiner Initial	Desig. ID	Document
<i>JP</i>	AS	International Search Report (Application No. PCT/JP03/16354) dated March 9, 2004
<i>JP</i>	AT	International Preliminary Examination Report (Application No. PCT/JP03/16354) dated April 20, 2004 with partial translation

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